SGS-THOMSON MICROELECTRONICS

M54HC237
M74HC237

3 TO 8 LINE DECODER LATCH

- LOW POWER DISSIPATION
  I_{CC} = 4 μA (MAX.) at T_A = 25°C
- HIGH NOISE IMMUNITY
  V_{NIH} = V_{NIL} = 28% V_{CC} (Min.)
- OUTPUT DRIVE CAPABILITY
  10 LSTTL LOADS
- SYMMETRICAL OUTPUT IMPEDANCE
  $|I_{OH}|$ = I_{OL} = 4 mA (MIN.)
- BALANCED PROPAGATION DELAYS
  t_{PLH} = t_{PHL}
- WIDE OPERATING VOLTAGE RANGE
  V_{CC} (OPR) = 2V to 6V
- PIN AND FUNCTION COMPATIBLE
  WITH 54/74LS237

B1N
Plastic Package

F1
Ceramic Frit Seal Package

M1
Micro Package

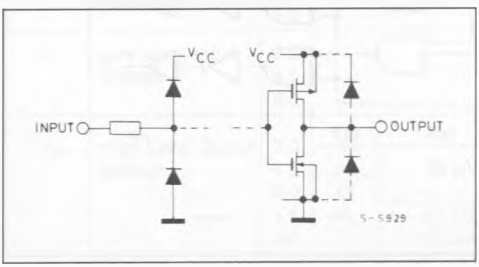
C1
Plastic Chip Carrier

ORDERING NUMBERS:
M54HC237 F1
M74HC237 B1N
M74HC237 F1
M74HC237 C1
M74HC237 M1

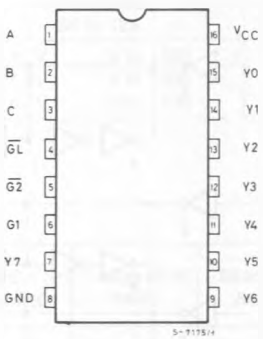
DESCRIPTION

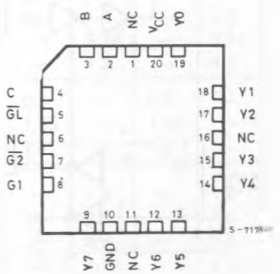
The M54/74HC237 is a high speed CMOS 3 TO 8 LINE DECODER LATCH fabricated in silicon gate C²MOS technology.
It has the same high speed performance of LSTTL combined with true CMOS low power consumption. When $\overline{GL}$ goes from low to high, the address present at the select inputs (A, B, C) is stored in the latches. As long as $\overline{GL}$ remains high no address changes will be recognized. Output enable controls, G1 and $\overline{G2}$ control the state of the outputs independantly of the select or latch-enable inputs. All of the outputs are low unless G1 is high and $\overline{G2}$ is low. The 'HC237 is ideally suited for the implementation of glitch-free decoders in stored-address applications in bus oriented systems. All inputs are equipped with protection circuits against static discharge and transient excess voltage.

INPUT AND OUTPUT EQUIVALENT CIRCUIT



PIN CONNECTIONS (top view)





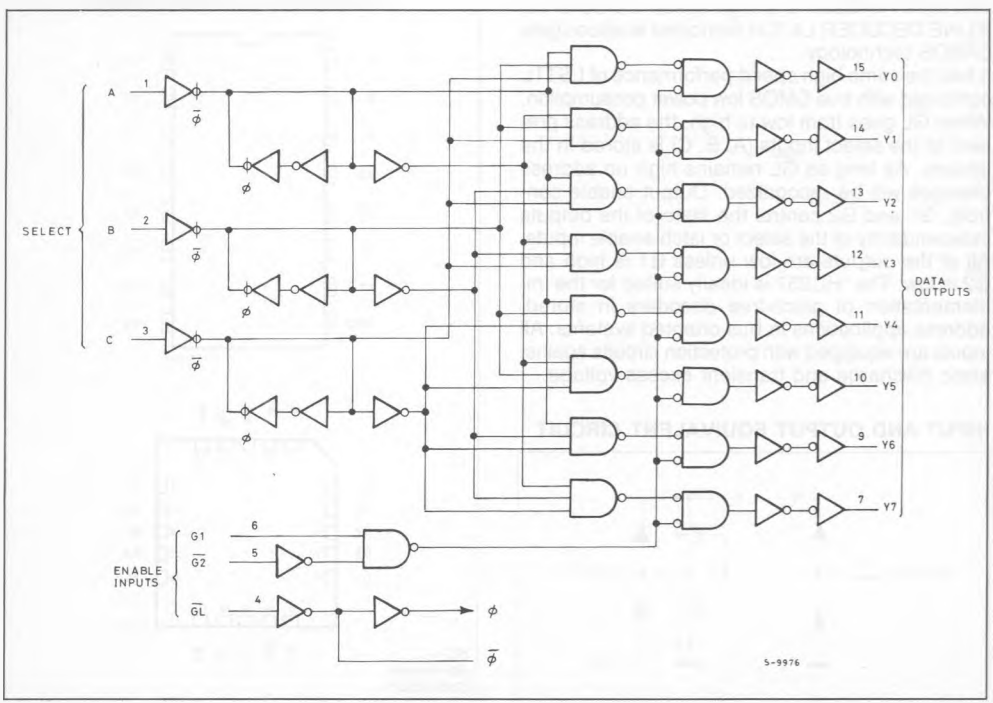
NC = No Internal Connection

TRUTH TABLE

INPUTS						OUTPUTS							
ENABLE			SELECT										
$\overline{GL}$	$\overline{G2}$	G1	C	B	A	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
X	X	L	X	X	X	L	L	L	L	L	L	L	L
X	H	X	X	X	X	L	L	L	L	L	L	L	L
L	L	H	L	L	L	H	L	L	L	L	L	L	L
L	L	H	L	L	H	L	H	L	L	L	L	L	L
L	L	H	L	H	L	L	L	H	L	L	L	L	L
L	L	H	L	H	H	L	L	L	H	L	L	L	L
L	L	H	H	L	L	L	L	L	L	H	L	L	L
L	L	H	H	L	H	L	L	L	L	L	H	L	L
L	L	H	H	H	L	L	L	L	L	L	L	H	L
L	L	H	H	H	H	L	L	L	L	L	L	L	H
H	L	H	X	X	X	OUTPUT CORRESPONDING TO STORED ADDRESS, H; ALL OTHERS, L							

X = DON'T CARE

LOGIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	−0.5 to 7	V
V_I	DC Input Voltage	−0.5 to V_{CC} + 0.5	V
V_O	DC Output Voltage	−0.5 to V_{CC} + 0.5	V
I_{IK}	DC Input Diode Current	± 20	mA
I_{OK}	DC Output Diode Current	± 20	mA
I_O	DC Output Source Sink Current Per Output Pin	± 25	mA
I_{CC} or I_{GND}	DC V_{CC} or Ground Current	± 50	mA
P_D	Power Dissipation	500 (*)	mW
T_{stg}	Storage Temperature	−65 to 150	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

(*) 500 mW: ≡65°C derate to 300 mW by 10 mW/°C: 65°C to 85°C

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter		Value		Unit
V_{CC}	Supply Voltage		2 to 6		V
V_I	Input Voltage		0 to V_{CC}		V
V_O	Output Voltage		0 to V_{CC}		V
T_A	Operating Temperature	74HC Series 54HC Series	− 40 to 85 −55 to 125		°C
t_r, t_f	Input Rise and Fall Time	V_{CC} = 2 V V_{CC} = 4.5V V_{CC} = 6 V	0 to 1000 0 to 500 0 to 400		ns

DC SPECIFICATIONS

Symbol	Parameter	V_{CC}	Test Condition		T_A = 25°C 54HC and 74HC			− 40 to 85°C 74HC		− 55 to 125°C 54HC		Unit
					Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V_{IH}	High Level Input Voltage	2.0			1.5	—	—	1.5	—	1.5	—	V
		4.5			3.15	—	—	3.15	—	3.15	—	
		6.0			4.2	—	—	4.2	—	4.2	—	
V_{IL}	Low Level Input Voltage	2.0			—	—	0.5	—	0.5	—	0.5	V
		4.5			—	—	1.35	—	1.35	—	1.35	
		6.0			—	—	1.8	—	1.8	—	1.8	
V_{OH}	High Level Output Voltage	2.0	V_{IN}	I_{OH}	1.9	2.0	—	1.9	—	1.9	—	V
		4.5	V_{IH}	−20 μA	4.4	4.5	—	4.4	—	4.4	—	
		6.0	or		5.9	6.0	—	5.9	—	5.9	—	
		4.5	V_{IL}	−4.0 mA	4.18	4.31	—	4.13	—	4.10	—	
		6.0		−5.2 mA	5.68	5.8	—	5.63	—	5.60	—	

DC SPECIFICATIONS (Continued)

Symbol	Parameter	V_{CC}	Test Condition		$T_A = 25°C$ 54HC and 74HC			−40 to 85°C 74HC		−55 to 125°C 54HC		Unit
					Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V_{OL}	Low Level Output Voltage	2.0	V_{IH} or V_{IL}	20 μA	—	0	0.1	—	0.1	—	0.1	V
		4.5			—	0	0.1	—	0.1	—	0.1	
		6.0			—	0	0.1	—	0.1	—	0.1	
		4.5		4.0 mA	—	0.17	0.26	—	0.33	—	0.40	
		6.0		5.2 mA	—	0.18	0.26	—	0.33	—	0.40	
I_{IN}	Input Leakage Current	6.0	$V_{IN} = V_{CC}$ or GND		—	—	±0.1	—	±1	—	±1	μA
I_{CC}	Quiescent Supply Current	6.0	$V_{IN} = V_{CC}$ or GND		—	—	4	—	40	—	80	

AC ELECTRICAL CHARACTERISTICS ($V_{CC} = 5V$, $T_A = 25°C$, $C_L = 15pF$)

Symbol	Parameter	Test Condition	54HC and 74HC			Unit
			Min.	Typ.	Max.	
t_{TLH} t_{THL}	Output Transition Time		—	4	8	ns
t_{PLH} t_{PHL}	Propagation Delay Time (A, B, C,-Yn)		—	19	30	ns
t_{PLH} t_{PHL}	Propagation Delay Time ($\overline{G1}$-Yn)		—	22	34	ns
t_{PLH} t_{PHL}	Propagation Delay Time (G1, $\overline{G2}$-Yn)		—	16	25	ns

AC ELECTRICAL CHARACTERISTICS ($C_L = 50pF$, Input $t_r = t_f = 6ns$)

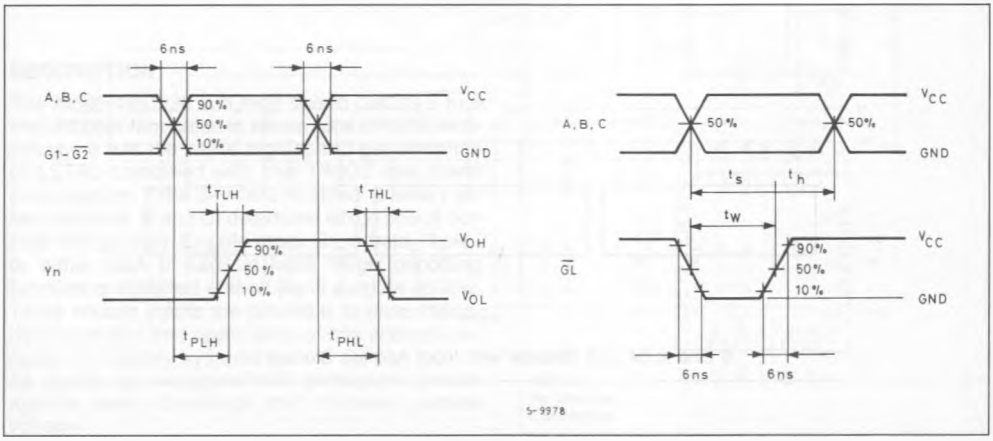
Symbol	Parameter	V_{CC}	Test Condition	$T_A = 25°C$ 54HC and 74HC			−40 to 85°C 74HC		−55 to 125°C 54HC		Unit
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
t_{TLH} t_{THL}	Output Transition Time (Q Outputs)	2.0		—	30	75	—	95	—	110	ns
		4.5		—	8	15	—	19	—	22	
		6.0		—	7	13	—	16	—	19	
t_{PLH} t_{PHL}	Propagation Delay Time (A, B, C,-Yn)	2.0		—	92	180	—	225	—	270	ns
		4.5		—	23	36	—	45	—	54	
		6.0		—	20	31	—	38	—	46	
t_{PLH} t_{PHL}	Propagation Delay Time ($\overline{GL}$-Yn)	2.0		—	104	200	—	250	—	300	ns
		4.5		—	26	40	—	50	—	60	
		6.0		—	22	34	—	43	—	51	

AC ELECTRICAL CHARACTERISTICS (Continued)

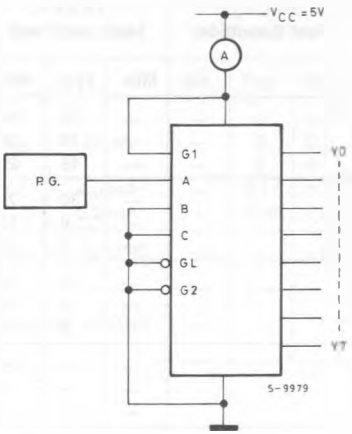
Symbol	Parameter	V_{CC}	Test Condition	$T_A = 25°C$ 54HC and 74HC			− 40 to 85°C 74HC		− 55 to 125°C 54HC		Unit
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
t_{PLH} t_{PHL}	Propagation Delay Time (G1, $\overline{G2}$-Yn)	2.0		—	76	150	—	190	—	225	ns
		4.5		—	19	30	—	38	—	45	
		6.0		—	16	26	—	33	—	38	
t_W	Minimum Pulse Width	2.0		—	30	75	—	95	—	110	ns
		4.5		—	8	15	—	19	—	22	
		6.0		—	7	13	—	16	—	19	
t_s	Minimum Set-up Time	2.0		—	12	50	—	65	—	75	ns
		4.5		—	3	10	—	13	—	15	
		6.0		—	3	9	—	11	—	13	
t_h	Minimum Hold Time	2.0		—	—	25	—	30	—	40	ns
		4.5		—	—	5	—	6	—	8	
		6.0		—	—	5	—	6	—	7	
C_{IN}	Input Capacitance			—	5	10	—	10	—	10	pF
C_{PD} (*)	Power Dissipation Capacitance			—	68	—	—	—	—	—	pF

Note (*) C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit)
Average operating current is: $I_{CC(opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$

SWITCHING CHARACTERISTICS TEST WAVEFORM

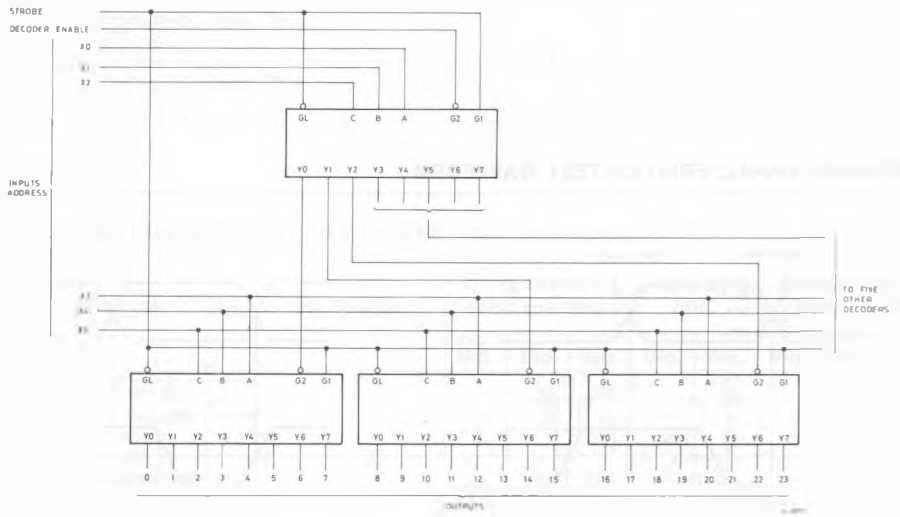


TEST CIRCUIT I_{CC} (Opr.)



INPUT TRANSITION TIME IS THE SAME AS THAT IN CASE OF SWITCHING CHARACTERISTICS TEST.

TYPICAL APPLICATION



6 Line to 64 Line Decoder with Input Address Storage